PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/736,386)
Filed:	December 15, 2003) Conf. No.: 6227
Title:	METHOD FOR CALCULATING HIGH-RESOLUTION WAFER PARAMETER PROFILES)))
Inventors:	Bruce Whitefield et al.)
Art Unit:	2128))
Examiner:	Hugh M. Jones)
Atty. Ref:	03-1345))

RESPONSE TO THE OFFICE ACTION MAILED OCTOBER 20, 2008

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed October 20, 2008, kindly consider the following remarks toward reconsideration of the present application.